

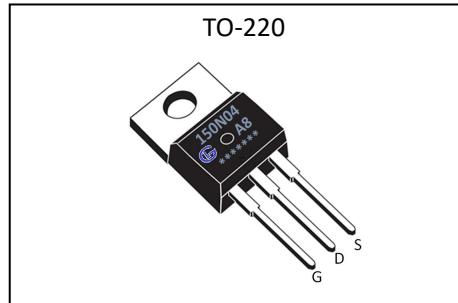
General Description

The GL150N04A8 uses advanced trench technology and design to provide excellent RDS(ON) with low gate charge. It can be used in a wide variety of applications. The package form is TO-220AB, which accords with the RoHS standard.

V _{DSS}	40	V
I _D	150	A
P _D	130	W
R _{DS(ON)type}	3.0	mΩ

Features

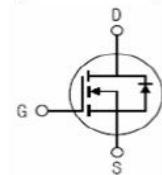
- Fast Switching
- Low Gate Charge and Rdson
- Low Reverse transfer capacitances
- 100% Single Pulse avalanche energy Test



Applications

- Power switching application
- Hard switched and high frequency circuits
- Uninterruptible power supply

Inner Equivalent Principium Chart



Absolute (T_c= 25°C unless otherwise specified)

Symbol	Parameter	Rating	Units
V _{DSS}	Drain-to-Source Voltage	40	V
I _D	Continuous Drain Current	150	A
	Continuous Drain Current T _c = 100 °C	90	A
I _{DM}	Pulsed Drain Current	400	A
V _{GS}	Gate-to-Source Voltage	±20	V
E _{AS} ^{a2}	Single Pulse Avalanche Energy	1100	mJ
E _{AR} ^{a1}	Avalanche Energy ,Repetitive	110	mJ
I _{AR} ^{a1}	Avalanche Current	50	A
dv/dt ^{a3}	Peak Diode Recovery dv/dt	5.0	V/ns
P _D	Power Dissipation	130	W
T _J , T _{stg}	Operating Junction and Storage Temperature Range	175, -55 to 175	°C
T _L	Maximum Temperature for Soldering	300	°C



GL150N04A8

GL Silicon N-Channel Power MOSFET

Electrical Characteristics ($T_c=25^\circ C$ unless otherwise specified)

OFF Characteristics						
Symbol	Parameter	Test Conditions	Rating			Units
			Min.	Typ.	Max.	
V_{DSS}	Drain to Source Breakdown Voltage	$V_{GS}=0V, I_D=250\mu A$	40	--	--	V
$\Delta V_{DSS}/\Delta T_J$	BVDSS Temperature Coefficient	$I_D=250\mu A$, Reference $25^\circ C$	--	0.1	--	$V/^\circ C$
I_{DSS}	Drain to Source Leakage Current	$V_{DS}=40V, V_{GS}=0V, T_a=25^\circ C$	--	--	1	μA
		$V_{DS}=32V, V_{GS}=0V, T_a=125^\circ C$	--	--	250	
$I_{GSS(F)}$	Gate to Source Forward Leakage	$V_{GS}=+20V$	--	--	1	μA
$I_{GSS(R)}$	Gate to Source Reverse Leakage	$V_{GS}=-20V$	--	--	-1	μA

ON Characteristics						
Symbol	Parameter	Test Conditions	Rating			Units
			Min.	Typ.	Max.	
$R_{DS(ON)}$	Drain-to-Source On-Resistance	$V_{GS}=10V, I_D=40A$	--	3.0	4.0	$m\Omega$
$V_{GS(TH)}$	Gate Threshold Voltage	$V_{DS}=V_{GS}, I_D=250\mu A$	2	--	4	V
Pulse width $t_p \leq 380\mu s, \delta \leq 2\%$						

Dynamic Characteristics						
Symbol	Parameter	Test Conditions	Rating			Units
			Min.	Typ.	Max.	
g_{fs}	Forward Transconductance	$V_{DS}=10V, I_D=20A$	25	--	--	S
C_{iss}	Input Capacitance	$V_{GS}=0V, V_{DS}=20V$	--	5400	--	pF
C_{oss}	Output Capacitance	$f=1.0MHz$	--	970	--	
C_{rss}	Reverse Transfer Capacitance		--	380	--	

Resistive Switching Characteristics						
Symbol	Parameter	Test Conditions	Rating			Units
			Min.	Typ.	Max.	
$t_{d(ON)}$	Turn-on Delay Time		--	23	--	ns
t_r	Rise Time	$I_D=20A, V_{DD}=20V$	--	25	--	
$t_{d(OFF)}$	Turn-Off Delay Time	$V_{GS}=10V, R_G=2.5\Omega$	--	70	--	
t_f	Fall Time		--	30	--	
Q_g	Total Gate Charge	$I_D=20A, V_{DD}=20V$	--	80	--	nC
Q_{gs}	Gate to Source Charge	$V_{GS}=10V$	--	11	--	
Q_{gd}	Gate to Drain ("Miller")Charge		--	18	--	

Source-Drain Diode Characteristics

Symbol	Parameter	Test Conditions	Rating			Units
			Min.	Typ.	Max.	
I_S	Continuous Source Current (Body Diode)		--	--	150	A
I_{SM}	Maximum Pulsed Current (Body Diode)		--	--	400	A
V_{SD}	Diode Forward Voltage	$I_S=40A, V_{GS}=0V$	--	--	1.5	V
t_{rr}	Reverse Recovery Time	$I_S=40A, T_j = 25^\circ C$	--	40	--	ns
Q_{rr}	Reverse Recovery Charge	$dI_F/dt=100A/\mu s, V_{GS}=0V$	--	48	--	nC

Pulse width $t_p \leq 380\mu s, \delta \leq 2\%$

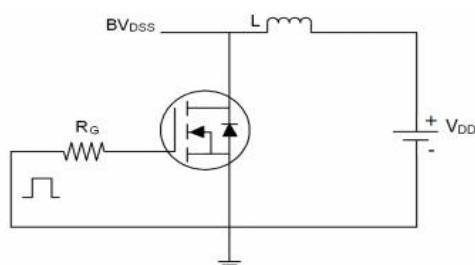
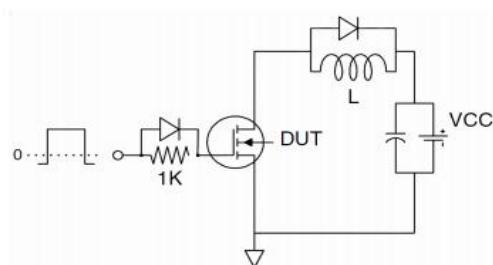
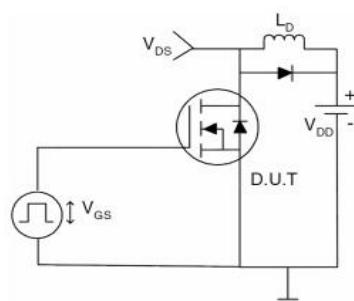
Thermal Characteristics

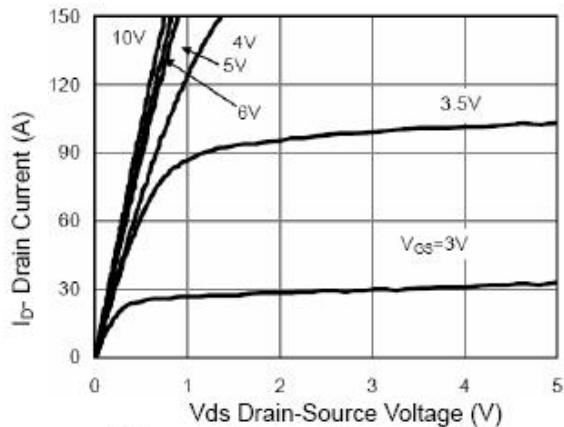
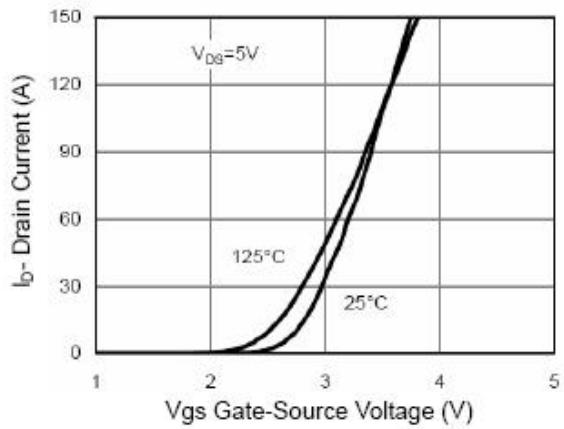
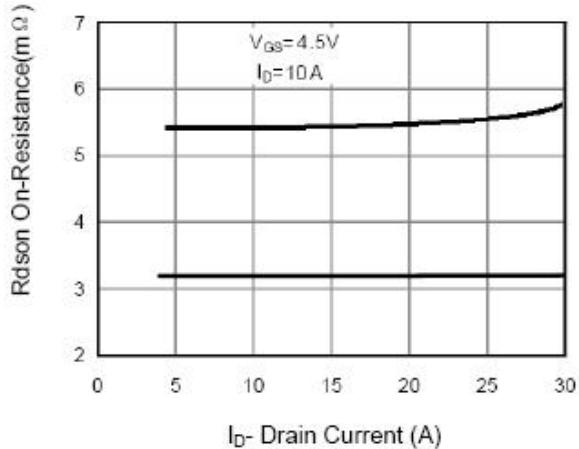
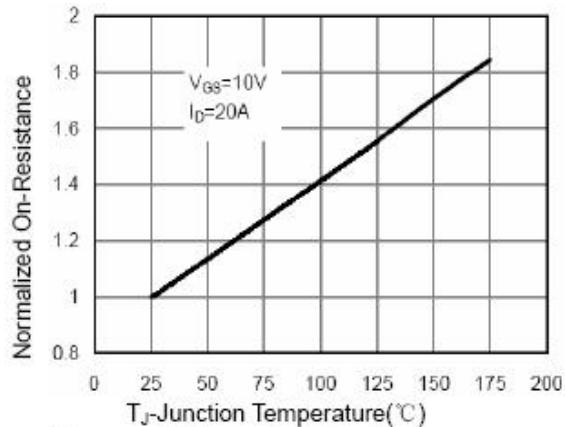
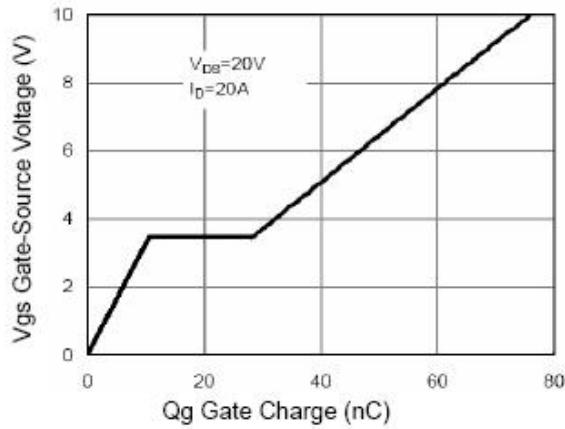
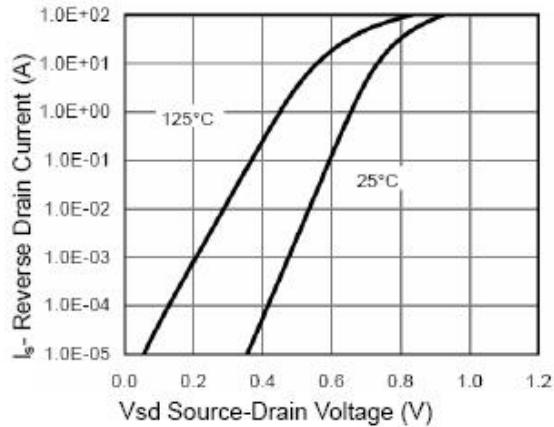
Symbol	Parameter	Typ.	Units
$R_{\theta JC}$	Junction-to-Case	1.15	°C/W

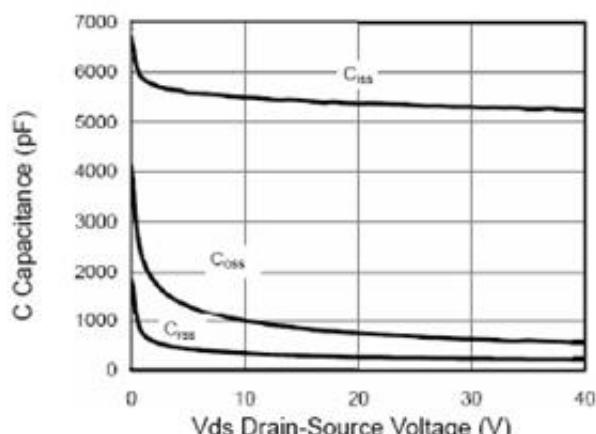
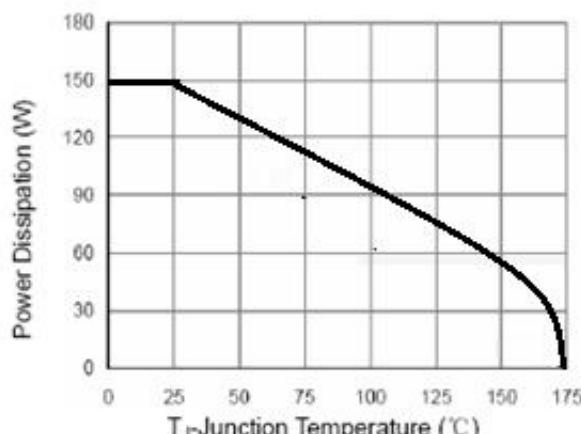
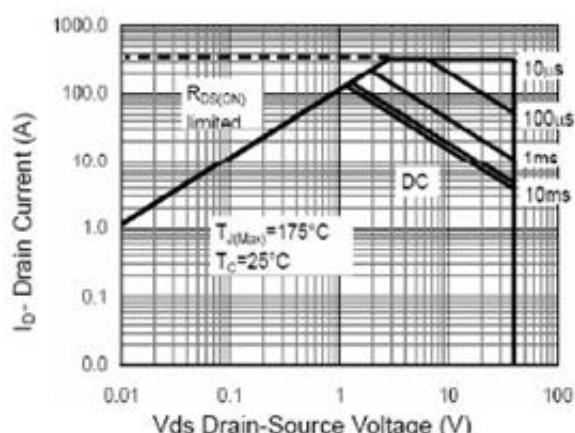
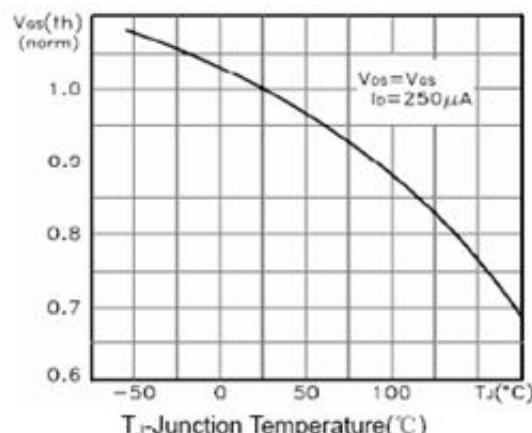
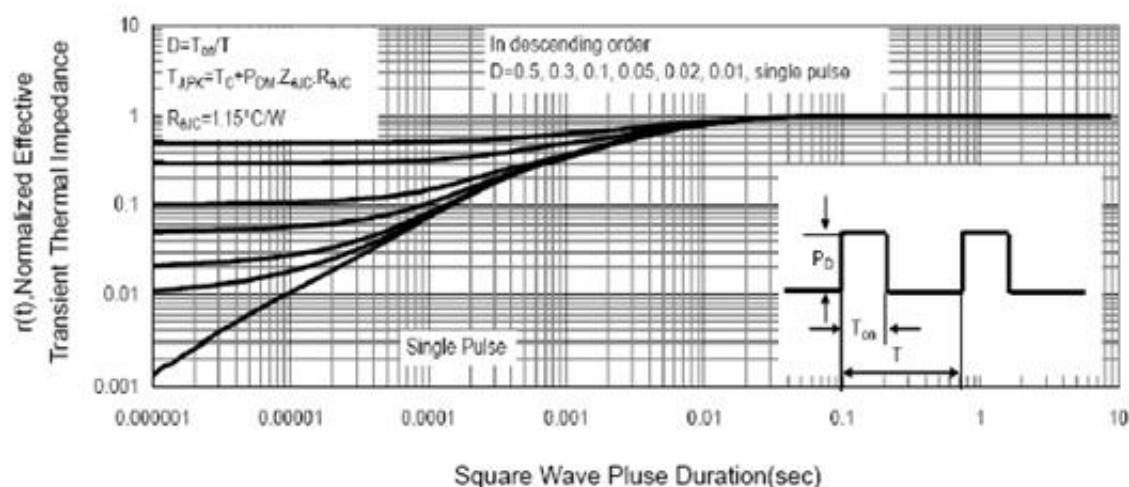
^{a1}: Repetitive rating; pulse width limited by maximum junction temperature

^{a2}: E_{AS} condition : $T_j=25^\circ C, V_{DD}=30V, V_G=10V, L=0.5mH, R_g=25\Omega$

^{a3}: $I_{SD} = 150A, di/dt \leq 100A/\mu s, V_{DD} \leq BV_{DS}, \text{Start } T_j=25^\circ C$

Test Circuits
1) E_{AS} test Circuits

2) Gate charge test Circuit:

3) Switch Time Test Circuit:


Characteristics Curves

Figure 1 Output Characteristics

Figure 2 Transfer Characteristics

Figure 3 Rdson- Drain Current

Figure 4 Rdson-JunctionTemperature

Figure 5 Gate Charge

Figure 6 Source- Drain Diode Forward


Figure 7 Capacitance vs Vds

Figure 9 Power De-rating

Figure 8 Safe Operation Area

Figure 10 $V_{GS(th)}$ vs Junction Temperature

Figure 11 Normalized Maximum Transient Thermal Impedance